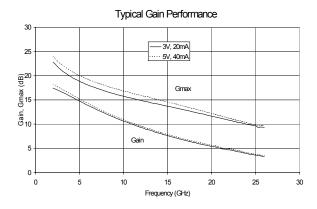


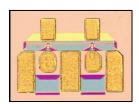
Product Description

Sirenza Microdevices' SPF-2000 is a high linearity, low noise $0.25\mu m$ pHEMT. This $300\mu m$ device is ideally biased at 3V,20mA for lowest noise performance. At 5V,40mA the device delivers excellent output TOI of 32 dBm. It provides ideal performance as driver stages in many commercial, industrial and military LNA applications.



SPF-2000

Low Noise High Linearity pHEMT GaAs FET 0.1 - 12 GHz Operation



Product Features

- 15 dB Gmax at 12GHz
- 1.25 dB F_{MIN} at 12 GHz
- +32 dBm Output IP3 at 12GHz
- +20 dBm Output Power at 1dB Compression

Applications

- High IP3 LNA for VSAT, LMDS, Cellular Systems and Instrumentation
- Broadband Amplifiers

| Symbol | Device Characteristics: | Test Conditions, Vds = 3V, lds = 20mA, T = 25°C (unless otherwise noted) | Test Frequency | U n its | M in . | Тур. | Max. |
|--------------------|--------------------------------------|---|--|----------------------------------|----------|------------------------------|-------------|
| Gmax | Maximum Available Gain [2] | $Z_s = Z_s^*, Z_L = Z_L^*$ | 1.9 GHz 4.0 GHz 12.0 GHz | d B d B d B | 21 13 | 25 23 15 | 25 17 |
| S 21 | Insertion Gain [2] | $Z_s = Z_L = 50 \text{ Ohms}$ | 1.9 GHz | d B | 16 | 18 | 20 |
| N F _{MIN} | Minimum Noise Figure | $Z_s = Gamma-opt, Z_L = Z_L^*$ | 2.0 GHz 4.0 GHz 12.0 GHz | d B d B d B | - | 0.5 0.6 1.2 | - |
| P _{1dB} | Output 1dB Compression Point | $V_{DS} = 5V, I_{DS} = 40 \text{ mA}$ $V_{DS} = 3V, I_{DS} = 20 \text{ mA}$ $V_{DS} = 5V, I_{DS} = 40 \text{ mA}$ $V_{DS} = 5V, I_{DS} = 40 \text{ mA}$ $V_{DS} = 3V, I_{DS} = 20 \text{ mA}$ | 2.0 GHz 2.0 GHz 12.0 GHz 12.0 GHz | d B m d B m d B m d B m | - | 20.0 15.0 21 18 | - - - |
| G _{1dB} | Gain at 1dB Compression Point | $V_{DS} = 5V, I_{DS} = 40 \text{ mA}$ $V_{DS} = 3V, I_{DS} = 20 \text{ mA}$ $V_{DS} = 5V, I_{DS} = 40 \text{ mA}$ $V_{DS} = 5V, I_{DS} = 40 \text{ mA}$ $V_{DS} = 3V, I_{DS} = 20 \text{ mA}$ | 2.0 GHz 2.0 GHz 12.0 GHz 12.0 GHz | d B m d B m d B m d B m | - | 17.7 17.0 13.0 11.0 | - - - |
| O IP ₃ | Output Third Order Intercept Point | $\begin{array}{c} V_{DS} = 5V, I_{DS} = 40\text{m A} \\ V_{DS} = 3V, I_{DS} = 20\text{m A} \\ V_{DS} = 5V, I_{DS} = 40\text{m A} \\ V_{DS} = 3V, I_{DS} = 20\text{m A} \end{array}$ | 2.0 GHz 2.0 GHz 12.0 GHz 12.0 GHz | d B m d B m d B m d B m | | 32 28 32 30 | - - - |
| I _{DSS} | Saturated Drain Current [2] | | | m A | 30 | 8 5 | 140 |
| V _P | Pinchoff Voltage [1] | V _{DS} = 2V, I _{DS} = 0.150 mA | | V | -1.5 | -1.0 | -0.5 |
| G _M | Transconductance | V _{GS} = -0.25V | | m S | - | 112 | - |
| B V _{g s} | Gate to Source Breakdown Voltage [1] | I _{GS} = 0.3 m A, drain open | | V | - | -17 | -8 |
| B V _{GD} | Gate to Drain Breakdown Voltage [1] | $I_{GD} = 0.3 \text{m A}, V_{GS} = -3.0 \text{V}$ | | V | - | -17 | -8 |
| R _{TH} | Thermal Resistance | | | C /W | | 110 | |
| V _{DS} | Operating Voltage [3] | Drain-source | | ٧ | | | 5.5 |
| I _{D Q} | Operating Current [3] | Drain-source, quiescent | | m A | | | 55 |
| PDISS | Power Dissipation [3] | | | W | | | 0.2 |

^{[1] 100%} tested - DC parameters tested on wafer.

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^[2] Sample tested - Samples pullied from each wafer lot. Sample test specifications are based on statistical data from sample test measurements.

^[3] $V_{DS} * I_{DQ} < P_{DISS}$ is recommended for continuous reliable operation.



Preliminary

SPF-2000 Low Noise High Linearity FET

Absolute Maximum Ratings

Operation of this device beyond any one of these parameters may cause permanent damage.

MTTF is inversely proportional to the device junction temperature. For junction temperature and MTTF considerations the operating conditions should also satisfy the following experssions:

$$P_{DC} - P_{OUT} < (T_{J} - T_{L}) / R_{TH}$$

where:

 $P_{DC} = I_{DS} * V_{DS} (W)$ $P_{OUT} = RF Output Power (W)$ $T_{J} = Junction Temperature (°C)$ $T_{L} = Lead Temperature (pin 4) (°C)$ $R_{TM} = Thermal Resistance (°C/W)$

| Parameter | Symbol | Value | Unit |
|---------------------------|-------------------|------------------|------|
| Drain Current | I _{DS} | I _{DSS} | mA |
| Forward Gate Current | I _{GSF} | 0.3 | mA |
| Reverse Gate Current | I _{GSR} | 0.3 | mA |
| Drain-to-Source Voltage | V _{DS} | +7 | ٧ |
| Gate-to-Drain Voltage | V _{GD} | -8 | V |
| Gate-to-Source Voltage | V _{GS} | <-5 or >0 | V |
| RF Input Power | P _{IN} | 100 | mW |
| Operating Temperature | T _{OP} | -40 to +85 | °C |
| Storage Temperature Range | T _{stor} | -40 to +150 | °C |
| Power Dissipation | P _{DISS} | 600 | mW |
| Channel Temperature | T _J | +150 | °C |

Assembly Instructions:

The recommended die attach is conductive epoxy or AuSn (80/20) solder with limited exposure to temperatures at or above 300C. The preferred wirebond method is thermo-compression wedge bond using 0.7 mil gold wire with a maximum stage temperature of 200C. Aluminum wire should not be used.

Design Data:

Complete design data including S-parameters, noise parameters, and large signal model are available upon request by contacting applications support at baredie-apps@sirenza.com





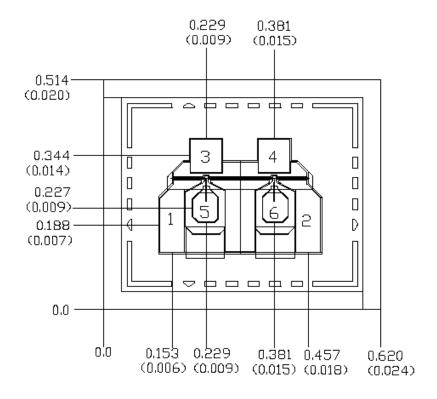
Preliminary

SPF-2000 Low Noise High Linearity FET

Part Number Ordering Information

| Part Number | Reel Size | Devices/Pack |
|-------------|-----------|--------------|
| SPF-2000 | Gel Pak | 100 |

Mechanical Drawing



Units: millimeters (inches) Thickness: 0.1016 (0.004)

Chip edge to bond pad dimensions are shown to center of bond pad

Chip size tolerance: +/- 0.051 (0.002)

Bond Pad #1,#2 (Source) 0.056 x 0.123 (0.002 x 0.005) Bond Pad #3,#4 (Drain) 0.070 x 0.074 (0.003 x 0.003) Bond Pad #5,#6 (Gate) 0.056 x 0.065 (0.002 x 0.003)

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